

Abstracts

Full Two-Port On-Wafer Vector Network Analysis to 120 GHz Using Active Probes

R. Yu, M. Reddy, J. Pusi, S. Allen, M. Case and M. Rodwell. "Full Two-Port On-Wafer Vector Network Analysis to 120 GHz Using Active Probes." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1339-1342.

A millimeter-wave full two port on-wafer vector network analyzer (VNA) is implemented with monolithic GaAs directional time-domain reflectometer integrated circuits mounted directly on low-loss microwave wafer probes. The VNA performs S-parameter measurements to 120 GHz with ± 0.2 dB repeatability using a Line-Reflect-Match calibration method.

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